

JMS4710N

Product Preview

30V Dual Asymmetric N-Channel MOSFET



Features

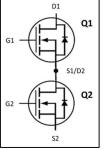
- Advanced shielded-gate technology
- Ultra-low on-resistance and gate-charge
- RoHS compliant



Product Summary								
Device	Q1	Q2						
V _{DS}	30V	30V						
D	8.3mΩ (Typ.)	6.9mΩ (Typ.)						
R _{DS} (ON)	10.7mΩ (Max.)	8.9mΩ (Max.)						
I _D	18A ⁽¹⁾	18A ⁽¹⁾						

Applications

- Motor controllers
- DC-to-DC convertors
- Battery-driven electronic products, electrical equipment and machines





Ordering Information

Part Number	Marking	Package	Packaging
JMS4710N	MS4710N	DFN3x3 Dual Asymmetric	Tape & Reel



Absolute Maximum Ratings

Do no monto n	Doromotor Symbol Limit		nit	Unit
Parameter	Symbol	Q1	Q2	Unit
Drain-to-Source Voltage	V _{DS}	30	30	V
Gate-to-Source Voltage	V _{GS}	±20	±20] V
Continuous Drain Current (Tc = 25°C) (1),(2)	ID	18	18	
Continuous Drain Current (Tc = 100°C) (1),(2)	ID	18	18	
Continuous Drain Current (T _A = 25°C) (3),(4)	lο	11	12	A
Continuous Drain Current (T _A = 100°C) (3),(4)	ID	7	8	
Pulsed Drain Current (5)	I _{DM}	72	72	
Power Dissipation (T _C = 25°C)	P _D	22.7	25	W
Linear Derating Factor	-	0.18	0.2	W/°C
Single Pulse Avalanche Energy ⁽⁶⁾	Eas	12	17	mJ
Avalanche Current ⁽⁷⁾	las	11	13	Α
Junction Temperature	Tı	-55 to 150	-55 to 150	°C
Storage Temperature	T _{STG}	-55 to 150	-55 to 150	

Thermal Characteristics

Dovometer	Cumbal	М	Unit	
Parameter	Symbol	Q1	Q2	
Junction-to-Ambient Thermal Resistance (4)	R _{0JA}	62	62	°C /\\
Junction-to-Case Thermal Resistance	Rөлс	5.5	5.0	°C/W

- (1) Limit by package.
- (2) Rated according to $R_{\theta \text{JC}}.$
- (3) Rated according to $R_{\theta JA}.$
- (4) Surface–mounted on 1 inch² FR4 board, 2 oz Cu.
- (5) Limited by maximum T_J.
- (6) Starting $T_J = 25$ °C, L = 0.1mH, $V_{DD} = 20$ V, $V_{GS} = 10$ V.
- (7) Pulse width limited by maximum T_J .



Q1:

Static Electrical Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Drain-to-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = 250μA	30	-	-	٧
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0	-	2.0	V
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V	-	-	1	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Duain to Course On Resistance	D	V _{GS} = 10V, I _D = 13A	-	8.3	10.7	mΩ
Drain-to-Source On-Resistance	R _{DS(ON)}	V _{GS} = 4.5 V, I _D = 10A	-	13.3	17.2	mΩ

Dynamic Electrical Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Transconductance	g fs	V _{DS} = 5V, I _D = 10A	-	35	-	S
Total Gate Charge	Qg	V _{GS} = 10V,	-	8.8	-	
Gate-to-Source Charge	Qgs	V _{DS} = 15V,	-	1.2	-	nC
Gate-to-Drain Charge	Q _{gd}	I _D = 15A	-	1.8	-	
Turn-On Delay Time	t _{d(on)}		-	2.9	-	
Rise Time	tr	$V_{GS} = 10V, V_{DS} = 15V,$	-	2.8	-	
Turn-Off Delay Time	t _{d(off)}	I _D = 15A,	-	18	-	ns
Fall Time	t _f	$R_G = 3.0\Omega$	-	4	-	
Input Capacitance	Ciss	45777	-	530	-	
Output Capacitance	Coss	$V_{DS} = 15V$, $V_{GS} = 0V$, $f = 1MHz$	-	220	-	pF
Reverse Transfer Capacitance	C _{rss}		-	15	-	

Diode Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Voltage	V _{SD}	V _{GS} = 0V, I _S = 10A	-	0.8	-	V
Reverse Recovery Time	T _{rr}	V _{GS} = 0V, I _S = 10A,	-	16	-	ns
Reverse Recovery Charge	Qrr	dls/dt = 100A/μs	-	12	-	nC

(8) $T_J = 25$ °C unless otherwise specified.



Q1: Typical Electrical Characteristics

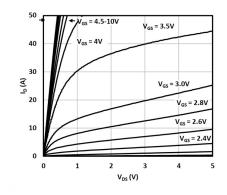


Fig. 1 Output characteristics

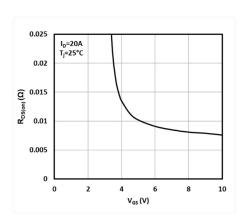


Fig.3 On-resistance vs. gate voltage

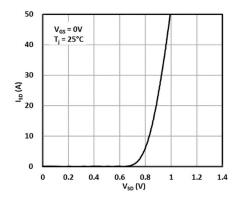


Fig.5 Source-to-drain diode forward characteristics

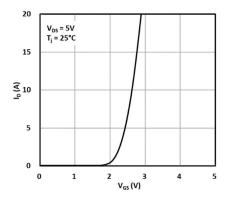


Fig. 2 Transfer characteristics

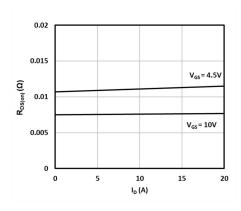


Fig.4 On-resistance vs. drain current

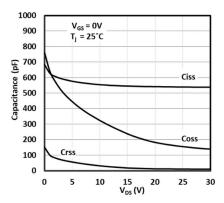


Fig.6 Capacitance vs. drain-to-source voltage



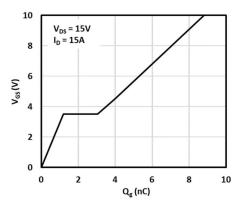


Fig.7 Gate-to-source voltage vs. gate charge

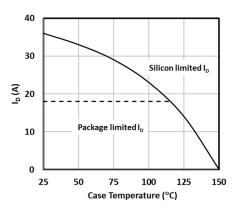


Fig.8 Maximum drain current vs. case temperature

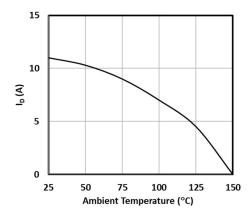


Fig. 9 Maximum drain current vs. ambient temperature



Q2:

Static Electrical Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Drain-to-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V$, $I_D = 250 \mu A$	30	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0	-	2.0	V
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V	-	-	1	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Duain to Course On Desistance	D	V _{GS} = 10V, I _D = 15A	-	6.9	8.9	mΩ
Drain-to-Source On-Resistance	R _{DS(ON)}	V _{GS} = 4.5 V, I _D = 10A	-	10.9	14.1	mΩ

Dynamic Electrical Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Transconductance	g fs	V _{DS} = 5V, I _D = 10A	-	40	-	S
Total Gate Charge	Qg	V _{GS} = 10V,	-	10.9	-	
Gate-to-Source Charge	Qgs	V _{DS} = 15V,	-	1.3	-	nC
Gate-to-Drain Charge	Q _{gd}	I _D = 15A	-	2.2	-	
Turn-On Delay Time	t _{d(on)}		-	3.1	-	
Rise Time	tr	$V_{GS} = 10V, V_{DS} = 15V,$	-	3.1	-	
Turn-Off Delay Time	t _{d(off)}	I _D = 15A,	-	27	-	ns
Fall Time	t _f	$R_G = 3.0\Omega$	-	5.8	-	
Input Capacitance	Ciss		-	680	-	
Output Capacitance	Coss	$V_{DS} = 15V$, $V_{GS} = 0V$, $f = 1MHz$	-	300	-	pF
Reverse Transfer Capacitance	Crss		-	20	-	

Diode Characteristics (8)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Voltage	V _{SD}	$V_{GS} = 0V$, $I_S = 10A$	-	0.8	-	V
Reverse Recovery Time	T _{rr}	$V_{GS} = 0V$, $I_S = 10A$,	-	18	-	ns
Reverse Recovery Charge	Qrr	dls/dt = 100A/μs	-	24	-	nC



Q2: Typical Electrical Characteristics

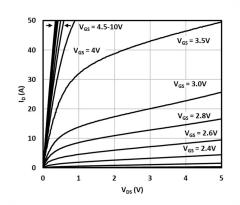


Fig. 1 Output characteristics

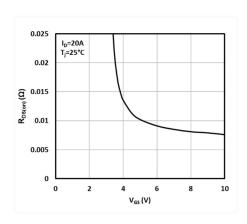


Fig.3 On-resistance vs. gate voltage

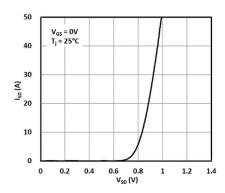


Fig.5 Source-to-drain diode forward characteristics

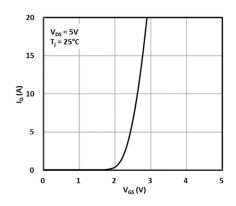


Fig. 2 Transfer characteristics

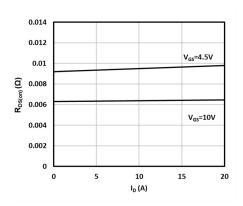


Fig.4 On-resistance vs. drain current

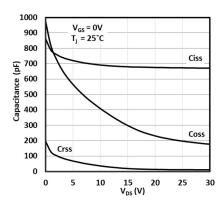


Fig.6 Capacitance vs. drain-to-source voltage



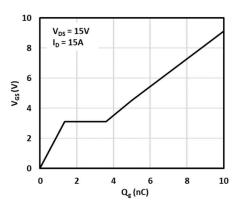


Fig.7 Gate-to-source voltage vs. gate charge

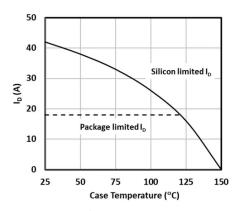


Fig.8 Maximum drain current vs. case temperature

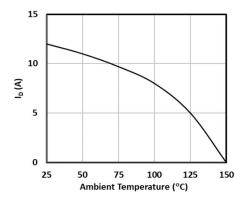
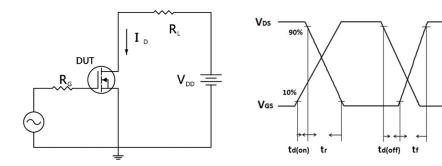


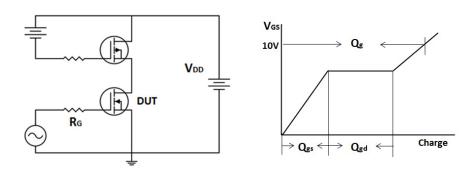
Fig. 9 Maximum drain current vs. ambient temperature



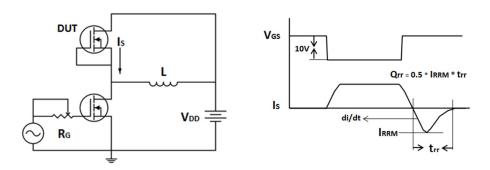
Test Circuits and Waveforms



Resistive switching time test circuit & waveforms

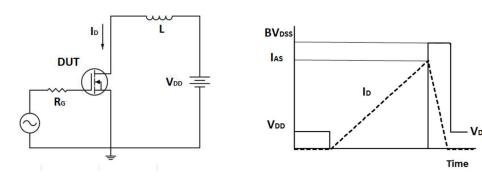


Gate charge test circuit & waveform



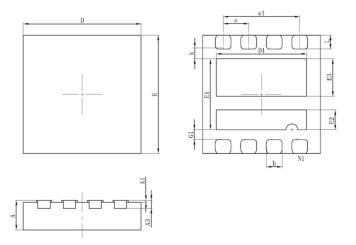
Peak diode recovery dv/dt test circuit & waveforms





Unclamped inductive switching test circuit & waveforms

Package Drawing



Symbol	Dimensions In Millimeters				
Symbol	Min.	Max.			
Α	0.700	0.800			
A1	0.000	0.050			
A3	0.203	REF.			
D	2.950	3.050			
Е	2.950	3.050			
D1	2.250	2.350			
E1	1.700	1.900			
E2	0.450	0.550			
E3	0.900	1.000			
k	0.200	0.300			
G1	0.200	0.300			
b	0.350	0.450			
е	0.650BSC				
e1	1.95BSC				
Ĺ	0.300	0.400			

DFN3x3 Dual Asymmetric



Revision History of JMS4710N Specification

Version	Change Items	Effective Date
1.00	Initial Release	04-Mar-20



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